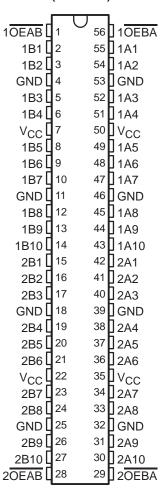
SCAS197B - JUNE 1990 - REVISED NOVEMBER 1996

- **Members of the Texas Instruments** Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines Directly
- Flow-Through Architecture Optimizes **PCB Layout**
- Distributed V_{CC} and GND Pin Configuration **Minimizes High-Speed Switching Noise**
- **EPIC™** (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- **Package Options Include Shrink Plastic** Small-Outline 300-mil (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center **Pin Spacings**

description

The 'ACT16861 are noninverting 20-bit transceivers designed for asynchronous communication between data buses. The control-function implementation minimizes external timing requirements.

The 'ACT16861 can be used as two 10-bit transceivers or one 20-bit transceiver. They allow data transmission from the A bus to the B bus or from the B bus to the A bus, depending upon the logic level at the output-enable (OEAB or OEBA) inputs. The output-enable inputs can be used to disable the device so that the buses are effectively **54ACT16861...WD PACKAGE** 74ACT16861...DL PACKAGE (TOP VIEW)



The 74ACT16861 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16861 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74ACT16861 is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

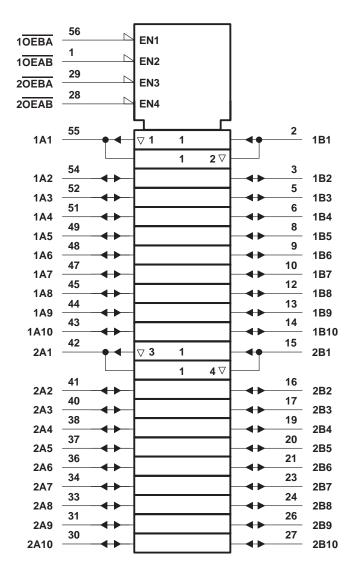
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FUNCTION TABLE (each 10-bit section)

INP	UTS	OPERATION
OEAB	OEBA	OPERATION
L	L	Latch A and B (A = B)
L	Н	A to B
Н	L	B to A
Н	Н	Isolation

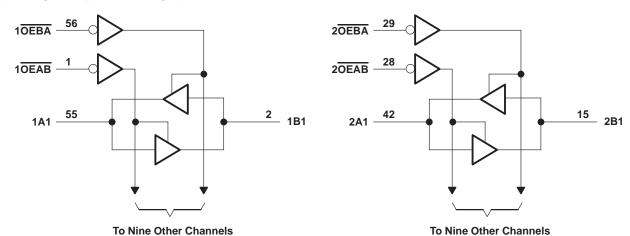
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±500 mA
Maximum power package dissipation at T _A = 55°C (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

recommended operating conditions (see Note 3)

		54ACT16861			74ACT16861			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2	į	42	2			V
V _{IL}	Low-level input voltage		S.	0.8			0.8	V
VI	Input voltage	0	Q	VCC	0		VCC	V
VO	Output voltage	0	Ç	VCC	0		VCC	V
IOH	High-level output current	\(\lambda\)	20	-24			-24	mA
loL	Low-level output current	D'AZ	,	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	Vaa	T,	_Δ = 25°C	;	54ACT	16861	74ACT	16861	UNIT	
		TEST CONDITIONS	v _{CC}	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		10.1 - 50.11A	4.5 V	4.4			4.4		4.4			
		I _{OH} = -50 μA	5.5 V	5.4			5.4		5.4			
Vон		I _{OH} = -24 mA	4.5 V	3.94			3.8		3.8		V	
		10H = -24 IIIA	5.5 V	4.94			4.8		4.8			
		I _{OH} = -75 mA [†]	5.5 V				3.85		3.85			
		I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V	
		ΙΟΣ = 30 μΑ	5.5 V			0.1		0.1		0.1		
VOL		la 24 mA	4.5 V			0.36		0.44		0.44		
		I _{OL} = 24 mA	5.5 V			0.36	,	0.44		0.44		
		I _{OL} = 75 mA [†]	5.5 V				05	1.65		1.65		
IĮ	Control inputs	V _I = V _{CC} or GND	5.5 V			±0.1	90	±1		±1	μΑ	
loz [‡]	A or B ports	$V_O = V_{CC}$ or GND	5.5 V			±0.5	Q	±5		±5	μΑ	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ	
ΔI _{CC} §		One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1		1	mA	
Ci	Control inputs	V _I = V _{CC} or GND	5 V		4.5						pF	
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	5 V		17						pF	

T Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (OUTPUT)	ТО	T _A = 25°C			54ACT16861		74ACT16861		UNIT
		(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	B or A	3.1	6.5	9.2	3.1	10.4	3.1	10.4	ns
^t PHL			2.9	7.5	10	2.9	<u> </u>	2.9	11.1	
^t PZH	OEBA or OEAB	A or B	2.4	6.6	9	2.4	10	2.4	10	no
t _{PZL}			3.7	8.5	11.5	3.7	12.7	3.7	12.7	ns
t _{PHZ}	OEBA or OEAB	A or D	4.9	7.4	9.8	4.9	10.7	4.9	10.7	no
t _{PLZ}		A or B	4.5	6.9	9.3	4.5	10	4.5	10	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CO	TYP	UNIT	
C _{pd} Power dissipation capacitance per transceiver	Outputs enabled	C 50 pE	f = 1 MHz	64	pF
	Outputs disabled	$C_L = 50 \text{ pF},$	t = 1 MHz	14	

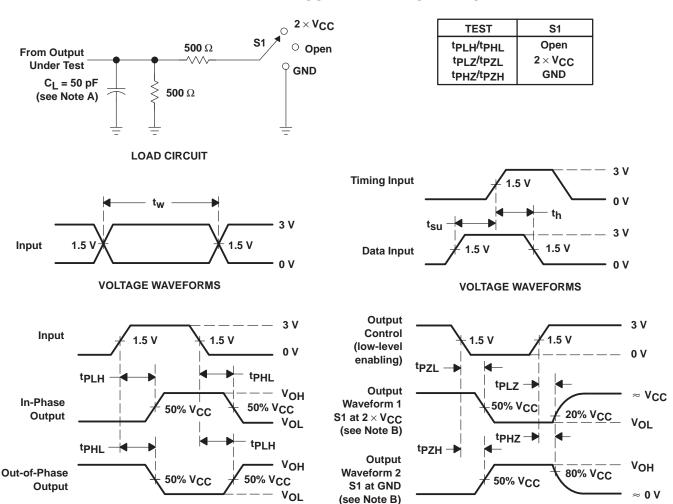


 $[\]mbox{\ensuremath{\mbox{\fontfamily{150}}}}\xspace For I/O ports, the parameter I_{OZ}$ includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

VOLTAGE WAVEFORMS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

VOLTAGE WAVEFORMS

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50~\Omega$, $t_f = 3~ns$, $t_f = 3~ns$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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